



SLOVENSKI STANDARD
oSIST prEN IEC 63185:2024
01-julij-2024

Merjenje kompleksne permisivnosti za dielektrične podlage z nizkimi izgubami, uravnovežene z metodo krožnega diskastega resonatorja

Measurement of the complex permittivity for low-loss dielectric substrates balanced-type circular disk resonator method

Messung der komplexen Dielektrizitätskonstante für verlustarme dielektrische Substrate nach dem symmetrischen Kreisscheibenresonatorverfahren

Méthode au résonateur à disque circulaire de type symétrique pour mesurer la permittivité complexe des substrats diélectriques à faible perte

Ta slovenski standard je istoveten z: prEN IEC 63185:2024

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TITLE:

Measurement of the complex permittivity for low-loss dielectric substrates balanced-type circular disk resonator method

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

MEASUREMENT OF THE COMPLEX PERMITTIVITY FOR LOW-LOSS DIELECTRIC SUBSTRATES BALANCED-TYPE CIRCULAR DISK RESONATOR METHOD

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